# SPIRE FPU AND JFET BOXES MECHANICAL/THERMAL DUMMY

# **Technical Proposal**

in response to

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# CONTENTS

I

2. APPLICABLE DOCUMENTS       5         3. LIST OF ACRONYMS/TERMS       5         4. PROPOSED DESIGN       6         4.1       SPIRE FPU       6         4.1.1       Overview       6         4.1.2       Mechanical Design       6         4.1.3       Nermal Design       7         4.1.4       Internal Design       7         4.1.4       Internal Design       7         4.2.1       Overview       7         4.2.2       Mechanical Design       7         4.2.3       Overview       7         4.2.4       Mechanical Design       7         4.3.1       Overview       8         4.3.2       Mechanical Design       8         4.3.3       Thermal Design       8         5.       OUTLINE OF WORK       9         5.1       WORKPACKAGE BREAXDOWN       9         5.2       WORKPACKAGE BREAXDOWN       9         5.1       WORKPACKAGE BREAXDOWN       9         5.2       WORKPACKAGE BREAXDOWN       9         5.2       WORKPACKAGE BREAXDOWN       9         5.2       WORKPACKAGE BREAXDOWN       9         5.2       WORKPACKAGE BREAXDOWN <th>1.</th> <th>INTRO</th> <th>DUCTION</th> <th> 5</th>	1.	INTRO	DUCTION	5
3.         LIST OF ACRONYMS/TERMS         5           4.         PROPOSED DESIGN	2.	APPLI	CABLE DOCUMENTS	5
4.       PROPOSED DESIGN	3.	LIST (	DF ACRONYMS/TERMS	5
4.         FROFOSED DESIGN         0           4.1         SPIRE FPU         6           4.1.1         Overview         6           4.1.2         Mechanical Design         6           4.1.3         Internal Earness Routing         7           4.1.4         Internal Harness Routing         7           4.2.1         Overview         7           4.2.2         SPECTROMETER IFET         7           4.2.3         Photometrer JFET         8           4.3.1         Overview         8           4.3.2         Mechanical Design         7           4.3.3         Thermal Design         8           4.3.1         Overview         8           5.0         OUTLINE OF WORK         9           5.1         WORKPACKAGE DESCRIPTIONS         11           6.         PROPOSED MALV PROGRAMME         33           6.1.1         Procurement of structure         33           6.1.2         Manufacture of dummy parts         33           6.1.3         Procurement of resistors, thermistors and connectors         33           6.2.4         Genard         33           6.2.1         Genard         33           6.2.2 <th>4</th> <th></th> <th></th> <th>(</th>	4			(
4.1       SPIRE FPU       6         4.1.1       Overview       6         4.1.2       Mechanical Design       6         4.1.3       Thermal Design       7         4.1.4       Intercal Harness Routing       7         4.1.4       Intercal Harness Routing       7         4.2.1       Overview       7         4.2.2       SPECTROMETER JFET       7         4.2.3       Thermal Design       7         4.3.1       Overview       8         4.3.2       Mechanical Design       8         4.3.3       Thermal Design       8         4.3.4       Mechanical Design       8         4.3.5       Mechanical Design       8         5.0       OUTLINE OF WORK       9         5.1       WORKPACKAGE BREAKDOWN       9         5.2       WORKPACKAGE DESCRIPTIONS       11         6.       PROPOSED MAIV PROCRAMME       33         6.1.1       MANUFACTURE AND PROCUREMENT       33         6.1.2       Manufacture of dummy parts       33         6.1.3       Procurement of structure       33         6.1.4       Procurement of trestors, thermistors and connectors       33	4.	PROP	USED DESIGN	0
4.1.1       Overview       6         4.1.2       Mechanical Design       6         4.1.3       Thermal Design       7         4.1.4       Internal Harness Routing       7         4.2       SPECTROMETER IFET       7         4.2.1       Overview       7         4.2.2       Mechanical Design       7         4.2.3       Thermal Design       7         4.3.4       Thermal Design       7         4.3.5       Mechanical Design       8         4.3.1       Overview       8         4.3.2       Mechanical Design       8         4.3.3       Thermal Design       8         5.       OUTLINE OF WORK       9         5.1       WORKPACKAGE BREAKDOWN       9         5.2       WORKPACKAGE DESCRIPTIONS       11         6.       PROPOSED MAIV PROGRAMME       33         6.1.1       Procurement of structure       33         6.1.2       Manufacture of dummy parts       33         6.1.3       Procurement of resistors, thermistors and connectors       33         6.1.4       Procurement of resistors, thermistors and connectors       33         6.2.1       General       33	2	4.1 Si	PIRE FPU	6
4.1.2       Mechanical Design       6         4.1.3       Thermal Design       7         4.1.4       Internal Marness Routing       7         4.1.4       Internal Marness Routing       7         4.2.1       SPECTROMETER IFET       7         4.2.2       Mechanical Design       7         4.2.3       Thermal Design       7         4.3.9       Piorometrex IFET       8         4.3.1       Overview       8         4.3.2       Mechanical Design       8         4.3.3       Thermal Design       8         4.3.4       Thermal Design       8         5.5       OUTLINE OF WORK       9         5.1       WORKPACKAGE BREAKDOWN       9         5.2       WORKPACKAGE DESCEPTIONS       11         6.1       MANUFACTURE AND PROCUREMENT       33         6.1.1       Procurement of structure       33         6.1.2       Manufacture of dummy parts       33         6.1.3       Procurement of resistors, thermistors and connectors       33         6.2.4       Assembly       33         6.2.5       Cleaning       33         6.2.4       Assembly       33         6		4.1.1	Overview	6
4.1.3       Thermal Design		4.1.2	Mechanical Design	6
4.1.4       Internal Harness Routing       7         4.2       SPECTROMETER JFET       7         4.2.1       Overview       7         4.2.2       Mechanical Design       7         4.2.3       Thermal Design.       7         4.3.1       Overview       8         4.3.2       Mechanical Design.       8         4.3.3       Thermal Design.       8         4.3.3       Thermal Design.       8         5.       OUTLINE OF WORK.       9         5.1       WORKPACKAGE BREAKDOWN.       9         5.2       WORKPACKAGE DESCRIPTIONS       11         6.       PROPOSED MAIV PROGRAMME       33         6.1.1       PROUTEMENT OF Structure       33         6.1.2       Manufacture of dummy parts       33         6.1.3       Procurement of thermal straps       33         6.1.4       Procurement of fermal straps       33         6.2.1       General       33         6.3.2       Harnessing       33         6.3.3       Thermal       33         6.3.4       Thermal       33         6.3.5       Cleaning       33         6.3.6       VERIFICATION		4.1.3	Thermal Design	7
4.2       SPECTROMETER JFET       7         4.2.1       Overview       7         4.2.2       Mechanical Design       7         4.2.3       Thermal Design       7         4.3       PHOTOMETER JFET       8         4.3.1       Overview       8         4.3.2       Mechanical Design       8         4.3.3       Thermal Design       8         5.       OUTLINE OF WORK       9         5.1       WORKPACKAGE BREAKDOWN       9         5.2       WORKPACKAGE DESCRIPTIONS       11         6.       PROPOSED MAIV PROGRAMME       33         6.1       MANUFACTURE AND PROCUREMENT       33         6.1.1       Procurement of structure       33         6.1.2       Manufacture of dummy parts       33         6.1.3       Procurement of thermal straps       33         6.1.4       Procurement of thermal straps       33         6.2.1       General       33         6.2.1       General       33         6.3.2       Harnessing       33         6.3.3       Thermal       33         6.3.4       Thermal       33         6.3.5       Cleanning       3		4.1.4	Internal Harness Routing	7
4.2.1       Overview       7         4.2.2       Mechanical Design       7         4.3       Thermal Design       7         4.3       PhOTOMETER IFET       8         4.3.1       Overview       8         4.3.2       Mechanical Design       8         4.3.3       Thermal Design       8         4.3.3       Thermal Design       8         5.       OUTLINE OF WORK       9         5.1       WORKPACKAGE BREAKDOWN       9         5.2       WORKPACKAGE DESCRIPTIONS       11         6.       PROPOSED MAIV PROGRAMME       33         6.1       MANUFACTURE AND PROCUREMENT       33         6.1.1       Procurement of structure       33         6.1.2       Manufacture of dummy parts       33         6.1.3       Procurement of resistors, thermistors and connectors       33         6.2.4       Assembly       33         6.2.5       Cleannical       33         6.2.6       Cleannical       33         6.3.1       Mechanical       33         6.2.2       Mechanical       33         6.3.3       Hermal       33         6.3.4       Thermal	2	1.2 Si	PECTROMETER JFET	7
4.2.2       Mechanical Design       7         4.3       PHOTOMETER IFET       8         4.3.1       Overview       8         4.3.2       Mechanical Design       8         4.3.3       Thermal Design       8         4.3.3       Thermal Design       8         5.       OUTLINE OF WORK       9         5.1       WORKPACKAGE BREAKDOWN       9         5.2       WORKPACKAGE DESCRIPTIONS       11         6.       PROPOSED MAIV PROGRAMME       33         6.1       MANUFACTURE AND PROCUREMENT       33         6.1.1       Procurement of structure       33         6.1.2       Manufacture of dummy parts       33         6.1.3       Procurement of tresistors, thermistors and connectors       33         6.1.4       Procurement of resistors, thermistors and connectors       33         6.2.2       Mechanical       33         6.2.3       Harnessing       33         6.2.4       Arsembly       33         6.2.5       Cleaning       33         6.3.4       Vibration Test.       34         6.3.5       Verification of cleanliness       34         6.3.6       Vibration Test.       34<		4.2.1	Overview	7
4.2.3       Thermal Design		4.2.2	Mechanical Design	7
4.3       PHOTOMETER JFET       8         4.3.1       Overview       8         4.3.2       Mechanical Design       8         4.3.3       Thermal Design       8         5.       OUTLINE OF WORK       9         5.1       WORKPACKAGE BREAKDOWN       9         5.2       WORKPACKAGE DESCRIPTIONS       11         6.       PROPOSED MAIV PROGRAMME       33         6.1       MANUFACTURE AND PROCUREMENT       33         6.1.1       Procurement of structure       33         6.1.2       Manufacture of dummy parts       33         6.1.3       Procurement of thermal straps.       33         6.1.4       Procurement of resistors, thermistors and connectors       33         6.2.1       General       33         6.2.2       Mechanical       33         6.2.3       Harnessing       33         6.2.4       Thermal       33         6.2.5       Cleaning       33         6.3.6       VERIFICATION       33         6.3.7       Harnessing       33         6.3.8       Filternal       34         6.3.4       Hhermal       34         6.3.5       Cleanlines		4.2.3	Thermal Design	7
4.3.1       Overview       8         4.3.2       Mechanical Design       8         4.3.3       Thermal Design       8         5.       OUTLINE OF WORK       9         5.1       WORKPACKAGE BREAKDOWN       9         5.2       WORKPACKAGE DESCRIPTIONS       11         6.       PROPOSED MAIV PROGRAMME       33         6.1       MANUFACTURE AND PROCUREMENT       33         6.1.1       Procurement of structure       33         6.1.2       Manufacture of dummy parts       33         6.1.3       Procurement of thermal straps.       33         6.1.4       Procurement of thermal straps.       33         6.2       ASSEMBLY       33         6.2       ASSEMBLY       33         6.2.1       General       33         6.2.2       Mechanical       33         6.2.3       Harnessing       33         6.2.4       Thermal       33         6.2.5       Cleaning       33         6.3.1       Mechanical Inspection       33         6.3.2       Electrical       34         6.3.3       Thermal       34         6.3.4       Vibration Test.       3	2	1.3 P	HOTOMETER JFET	8
4.3.2       Mechanical Design       8         4.3.3       Thermal Design       8         5.       OUTLINE OF WORK       9         5.1       WORKPACKAGE BEAKDOWN       9         5.2       WORKPACKAGE DESCRIPTIONS       11         6.       PROPOSED MAIV PROGRAMME       33         6.1       MANUFACTURE AND PROCUREMENT       33         6.1.1       Procurement of structure       33         6.1.2       Manufacture of dummy parts       33         6.1.3       Procurement of thermal straps.       33         6.1.4       Procurement of structure       33         6.2.1       General       33         6.2.2       ASSEMBLY       33         6.2.3       Harnessing       33         6.2.4       Thermal       33         6.2.5       Cleaning       33         6.3.4       Vibration Test.       33         6.3.5       Cleaning       33         6.3.6       Vibration Test.       34         6.3.6       Vibration Test.       34         6.3.6       Vibration Test.       34         6.4.1       Transport.       34         6.4.2       Integration		4.3.1	Overview	8
4.3.3       Thermal Design		4.3.2	Mechanical Design	8
5. OUTLINE OF WORK		4.3.3	Thermal Design	8
5.1       WORKPACKAGE BREAKDOWN	5.	OUTL	INE OF WORK	9
5.2       WORKPACKAGE DESCRIPTIONS.       11         6.       PROPOSED MAIV PROGRAMME       33         6.1       MANUFACTURE AND PROCUREMENT.       33         6.1.1       Procurement of structure       33         6.1.2       Manufacture of dummy parts       33         6.1.3       Procurement of thermal straps       33         6.1.4       Procurement of resistors, thermistors and connectors       33         6.2.1       General       33         6.2.1       General       33         6.2.2       Mechanical       33         6.2.3       Harnessing       33         6.2.4       Thermal       33         6.2.5       Cleaning       33         6.3.1       Mechanical Inspection       33         6.3.2       Electrical       34         6.3.3       Thermal       34         6.3.4       Vibration Test.       34         6.3.5       Cleanliness       34         6.3.6       Verification of cleanliness       34         6.3.6       Verification of cleanliness       34         6.4.1       Transport.       34         6.4.2       Integration       34 <td< td=""><td>4</td><td>5.1 W</td><td>ORKPACKAGE BREAKDOWN</td><td> 9</td></td<>	4	5.1 W	ORKPACKAGE BREAKDOWN	9
6.       PROPOSED MAIV PROGRAMME       33         6.1       MANUFACTURE AND PROCUREMENT       33         6.1.1       Procurement of structure       33         6.1.2       Manufacture of dummy parts       33         6.1.3       Procurement of thermal straps       33         6.1.4       Procurement of resistors, thermistors and connectors       33         6.1.4       Procurement of resistors, thermistors and connectors       33         6.2.1       General       33         6.2.2       Mechanical       33         6.2.3       Harnessing       33         6.2.4       Thermal       33         6.2.5       Cleaning       33         6.3.6       VERFICATION       33         6.3.1       Mechanical Inspection       33         6.3.2       Electrical       34         6.3.4       Vibration Test.       34         6.3.5       Cleanliness       34         6.3.6       Verification of cleanliness       34         6.3.6       Verification of cleanliness       34         6.3.7       Cleanliness       34         6.3.8       Vibration Test       34         6.4.1       Transport <t< td=""><td>4</td><td>5.2 W</td><td>ORKPACKAGE DESCRIPTIONS</td><td>11</td></t<>	4	5.2 W	ORKPACKAGE DESCRIPTIONS	11
6.1       MANUFACTURE AND PROCUREMENT	6	PROP		33
6.1       MANUFACTURE AND PROCUREMENT.       33         6.1.1       Procurement of structure       33         6.1.2       Manufacture of dummy parts       33         6.1.3       Procurement of thermal straps.       33         6.1.4       Procurement of resistors, thermistors and connectors       33         6.1.4       Procurement of resistors, thermistors and connectors       33         6.2       ASSEMBLY       33         6.2.1       General       33         6.2.2       Mechanical       33         6.2.3       Harnessing       33         6.2.4       Thermal       33         6.3.5       Cleaning       33         6.3       VERIFICATION       33         6.3.1       Mechanical Inspection       33         6.3.2       Electrical       34         6.3.3       Thermal       34         6.3.4       Vibration Test       34         6.3.5       Cleanliness       34         6.3.6       Verification of cleanliness       34         6.4.1       Transport       34         6.4.2       Integration       34         7.1       GENERAL REQUIREMENTS       34	υ.	IKOI	USED MAIV I KOOKAMINE	55
6.1.1       Procurement of structure       33         6.1.2       Manufacture of dummy parts       33         6.1.3       Procurement of thermal straps	e	5.1 M	ANUFACTURE AND PROCUREMENT	33
6.1.2       Manufacture of dummy parts       33         6.1.3       Procurement of thermal straps       33         6.1.4       Procurement of resistors, thermistors and connectors       33         6.1.4       Procurement of resistors, thermistors and connectors       33         6.2       Assembly       33         6.2.1       General       33         6.2.2       Mechanical       33         6.2.3       Harnessing       33         6.2.4       Thermal       33         6.2.5       Cleaning       33         6.2.6       Cleaning       33         6.3       VERIFICATION       33         6.3.1       Mechanical Inspection       33         6.3.2       Electrical       34         6.3.3       Thermal       34         6.3.4       Vibration Test.       34         6.3.6       Verification of cleanliness       34         6.3.6       Verification of cleanliness       34         6.4.1       DELIVERY AND INTEGRATION       34         6.4.2       Integration       34         7.1       GENERAL REQUIREMENTS       34         7.1       GENERAL REQUIREMENTS       36		6.1.1	Procurement of structure	33
6.1.3       Procurement of thermal straps		6.1.2	Manufacture of dummy parts	33
6.1.4       Procurement of resistors, thermistors and connectors       33         6.2       ASSEMBLY       33         6.2.1       General       33         6.2.2       Mechanical       33         6.2.3       Harnessing       33         6.2.4       Thermal       33         6.2.5       Cleaning       33         6.2.6       Cleaning       33         6.2.7       VERIFICATION       33         6.3       VERIFICATION       33         6.3.1       Mechanical Inspection       33         6.3.2       Electrical       34         6.3.3       Thermal       34         6.3.4       Vibration Test       34         6.3.5       Cleanliness       34         6.4       DELIVERY AND INTEGRATION       34         6.4.1       Transport       34         6.4.2       Integration       34         7.1       GENERAL REQUIREMENTS       34         7.1       GENERAL REQUIREMENTS       36         7.2       FPU SPECIFIC REQUIREMENTS       36         7.3       SPECTROMETER JFET SPECIFIC REQUIREMENTS       37		6.1.3	Procurement of thermal straps	33
6.2       ASSEMBLY       33         6.2.1       General       33         6.2.2       Mechanical       33         6.2.3       Harnessing       33         6.2.4       Thermal       33         6.2.5       Cleaning       33         6.2.6       Cleaning       33         6.2.7       Cleaning       33         6.2.8       VERIFICATION       33         6.3.1       Mechanical Inspection       33         6.3.2       Electrical       34         6.3.3       Thermal       34         6.3.4       Vibration Test       34         6.3.5       Cleanliness       34         6.4       DELIVERY AND INTEGRATION       34         6.4.1       Transport       34         6.4.2       Integration       34         7.1       GENERAL REQUIREMENTS       34         7.1       GENERAL REQUIREMENTS       36         7.2       FPU SPECIFIC REQUIREMENTS       36         7.3       SPECTROMETER JFET SPECIFIC REQUIREMENTS       37		6.1.4	Procurement of resistors, thermistors and connectors	33
6.2.1       General       33         6.2.2       Mechanical       33         6.2.3       Harnessing       33         6.2.4       Thermal       33         6.2.5       Cleaning       33         6.2.6       Cleaning       33         6.2.7       Thermal       33         6.2.4       Thermal       33         6.2.5       Cleaning       33         6.2.6       Cleaning       33         6.3       VERIFICATION       33         6.3       Vectorical       34         6.3.2       Electrical       34         6.3.3       Thermal       34         6.3.4       Vibration Test       34         6.3.5       Cleanliness       34         6.4       DELIVERY AND INTEGRATION       34         6.4.1       Transport       34         6.4.2       Integration       34         7.1       GENERAL REQUIREMENTS       34         7.1       GENERAL REQUIREMENTS       36         7.3       SPECTROMETER JFET SPECIFIC REQUIREMENTS       36	6	5.2 A	SSEMBLY	33
6.2.2       Mechanical       33         6.2.3       Harnessing       33         6.2.4       Thermal       33         6.2.5       Cleaning       33         6.3       VERIFICATION       33         6.3       VERIFICATION       33         6.3.1       Mechanical Inspection       33         6.3.2       Electrical       34         6.3.3       Thermal       34         6.3.4       Vibration Test       34         6.3.5       Cleanliness       34         6.3.6       Verification of cleanliness       34         6.4       DELIVERY AND INTEGRATION       34         6.4.1       Transport       34         6.4.2       Integration       34         7.1       GENERAL REQUIREMENTS       34         7.2       FPU SPECIFIC REQUIREMENTS       36         7.3       SPECTROMETER JFET SPECIFIC REQUIREMENTS       37		6.2.1	General	33
6.2.3       Harnessing       33         6.2.4       Thermal       33         6.2.5       Cleaning       33         6.3       VERIFICATION       34         6.3.1       Mechanical Inspection       34         6.3.2       Electrical       34         6.3.3       Thermal       34         6.3.4       Vibration Test       34         6.3.5       Cleanliness       34         6.4       DELIVERY AND INTEGRATION       34         6.4.1       Transport       34         6.4.2       Integration       34         7.       COMPLIANCE MATRIX       34         7.1       GENERAL REQUIREMENTS       34         7.2       FPU SPECIFIC REQUIREMENTS       36         7.3       SPECTROMETER JFET SPECIFIC REQUIREMENTS       37		6.2.2	Mechanical	33
6.2.4       Thermal       33         6.2.5       Cleaning       33         6.3       VERIFICATION       33         6.3.1       Mechanical Inspection       33         6.3.2       Electrical       34         6.3.3       Thermal       34         6.3.4       Vibration Test       34         6.3.5       Cleanliness       34         6.3.6       Verification of cleanliness       34         6.4       DELIVERY AND INTEGRATION       34         6.4.1       Transport       34         6.4.2       Integration       34         7.       COMPLIANCE MATRIX       34         7.1       GENERAL REQUIREMENTS       34         7.2       FPU SPECIFIC REQUIREMENTS       36         7.3       SPECTROMETER JFET SPECIFIC REQUIREMENTS       37		6.2.3	Harnessing	33
6.2.5       Cleaning       33         6.3       VERIFICATION       33         6.3       Mechanical Inspection       33         6.3.1       Mechanical Inspection       33         6.3.2       Electrical       34         6.3.3       Thermal       34         6.3.4       Vibration Test.       34         6.3.5       Cleanliness       34         6.3.6       Verification of cleanliness       34         6.4       DELIVERY AND INTEGRATION       34         6.4.1       Transport.       34         6.4.2       Integration       34         7.       COMPLIANCE MATRIX       34         7.1       GENERAL REQUIREMENTS       34         7.2       FPU SPECIFIC REQUIREMENTS       36         7.3       SPECTROMETER JFET SPECIFIC REQUIREMENTS       37		6.2.4	Thermal	33
6.3       VERIFICATION       33         6.3.1       Mechanical Inspection       33         6.3.2       Electrical       34         6.3.3       Thermal       34         6.3.4       Vibration Test.       34         6.3.5       Cleanliness       34         6.3.6       Verification of cleanliness       34         6.4       DELIVERY AND INTEGRATION       34         6.4.1       Transport.       34         6.4.2       Integration       34         7.1       GENERAL REQUIREMENTS       34         7.2       FPU SPECIFIC REQUIREMENTS       36         7.3       SPECTROMETER JFET SPECIFIC REQUIREMENTS       37		6.2.5	Cleaning	33
6.3.1       Mechanical Inspection       33         6.3.2       Electrical       34         6.3.3       Thermal       34         6.3.4       Vibration Test       34         6.3.5       Cleanliness       34         6.3.6       Verification of cleanliness       34         6.3.6       Verification of cleanliness       34         6.4       DELIVERY AND INTEGRATION       34         6.4.1       Transport.       34         6.4.2       Integration       34         7.       COMPLIANCE MATRIX       34         7.1       GENERAL REQUIREMENTS       34         7.2       FPU SPECIFIC REQUIREMENTS       36         7.3       SPECTROMETER JFET SPECIFIC REQUIREMENTS       37	6	5.3 V	ERIFICATION	33
6.3.2       Electrical		6.3.1	Mechanical Inspection	33
6.3.3       Thermal       34         6.3.4       Vibration Test.       34         6.3.5       Cleanliness       34         6.3.6       Verification of cleanliness.       34         6.3.6       Verification of cleanliness.       34         6.4       DELIVERY AND INTEGRATION       34         6.4.1       Transport.       34         6.4.2       Integration.       34         7.       COMPLIANCE MATRIX       34         7.1       GENERAL REQUIREMENTS.       34         7.2       FPU SPECIFIC REQUIREMENTS       36         7.3       SPECTROMETER JFET SPECIFIC REQUIREMENTS       37		6.3.2	Electrical	34
6.3.4       Vibration Test		6.3.3	Thermal	34
6.3.5Cleanliness346.3.6Verification of cleanliness346.4DELIVERY AND INTEGRATION346.4.1Transport346.4.2Integration347.COMPLIANCE MATRIX347.1GENERAL REQUIREMENTS347.2FPU SPECIFIC REQUIREMENTS367.3SPECTROMETER JFET SPECIFIC REQUIREMENTS37		6.3.4	Vibration Test	34
6.3.6       Verification of cleanliness       34         6.4       DELIVERY AND INTEGRATION       34         6.4.1       Transport.       34         6.4.2       Integration       34         7.       COMPLIANCE MATRIX       34         7.1       GENERAL REQUIREMENTS       34         7.2       FPU SPECIFIC REQUIREMENTS       36         7.3       SPECTROMETER JFET SPECIFIC REQUIREMENTS       37		6.3.5	Cleanliness	34
6.4DELIVERY AND INTEGRATION346.4.1Transport.346.4.2Integration.347.COMPLIANCE MATRIX347.1GENERAL REQUIREMENTS.347.2FPU SPECIFIC REQUIREMENTS367.3SPECTROMETER JFET SPECIFIC REQUIREMENTS.37		6.3.6	Verification of cleanliness	34
6.4.1       Transport	6	5.4 D	ELIVERY AND INTEGRATION	34
6.4.2Integration347.COMPLIANCE MATRIX347.1GENERAL REQUIREMENTS347.2FPU SPECIFIC REQUIREMENTS367.3SPECTROMETER JFET SPECIFIC REQUIREMENTS37		6.4.1	Transport	34
7. COMPLIANCE MATRIX       34         7.1       GENERAL REQUIREMENTS       34         7.2       FPU SPECIFIC REQUIREMENTS       36         7.3       SPECTROMETER JFET SPECIFIC REQUIREMENTS       37		6.4.2	Integration	34
7.1GENERAL REQUIREMENTS	7.	COMP	LIANCE MATRIX	34
7.2       FPU Specific Requirements       36         7.3       Spectrometer JFET Specific Requirements       37	-	7.1 G	ENERAL REOUIREMENTS	34
7.3 SPECTROMETER JFET SPECIFIC REQUIREMENTS	, -	72 F	PU SPECIFIC REQUIREMENTS	36
				~

	7.4	PHOTOMETER JFET SPECIFIC REQUIREMENTS	37
8.	RIS	KS	39
9.	PRO	DPOSED PRODUCT ASSURANCE PLAN	40
10.	D	ELIVERABLE ITEMS	41

## **1. INTRODUCTION**

This document outlines the technical proposal to supply Astrium GmbH with mechanical and thermal dummies (MTDs) for the SPIRE focal plane unit (FPU), Photometer JFET box and Spectrometer JFET box. It makes reference to, and responds to, AD2 and Procurement Specification issued by Astrium for this project.

## **2. APPLICABLE DOCUMENTS**

AD1	Special Conditions of Tender	HP-2-ASED-AO-0020
AD2	Statement of Work	HP-2-ASED-SW-0029
AD3	Procurement Specification	HP-2-ASED-PS-0027

## 3. LIST OF ACRONYMS/TERMS

MTD	Mechanical Thermal Dummy
AIV	Manufacture, Assembly, Integration and Verification
FM	Flight Model (or equivalent)
FEA	Finite Element Analysis
FPU	Focal Plane Unit (of SPIRE)
BDA	Bolometer Detector Array (subsystem of SPIRE)
CAD	Computer Aided Design
CoG	Center of Gravity
MoI	Moment of Inertia
ESATAN	Thermal modelling software
WP	Workpackage

## 4. PROPOSED DESIGN

#### 4.1 SPIRE FPU

#### 4.1.1 Overview

It is proposed to supply the FPU and JFET units which make heavy use of structural parts made to FM specifications, with dummy masses used to represent internal subsystems such as mirrors and detectors. Thermally, the external interfaces would be the same as the FM. External electrical interfaces will mechanically be identical to the FM. Mounting and other mechanical interfaces will be the same as the FM.

#### 4.1.2 Mechanical Design

The following table outlines the proposed breakdown between FM structural and dummy mechanical parts: The parts described as "As FM" will be manufactured from the FM drawings using the same materials as for FM. In this way we can ensure that the mechanical properties and dynamic behaviour of the MTD will be very close to that of the FM.

Part	Source	Comments
SPIRE Optics Bench	As FM	
Photometer Cover	As FM	
Spectrometer Cover	As FM	
Photometer Detector Enclosure	As FM	
Spectrometer Detector Enclosure	As FM	
Spectrometer Box A-frames	As FM	
Mirror mounts	As FM	
Mirrors	Dummy Mass	
Baffles	Dummy Mass	
Cooler	Dummy Mass	
Bolometer Detector Arrays	Dummy Mass	
Spectrometer Mechanism	Dummy Mass	
Beam Steering Mechanism	Dummy Mass	
RF Filtering Connector Feedthroughs	Dummy Mass	Connectors to be as FM
Spectrometer Calibration Source	Dummy Mass	
Photometer Calibration Source	Dummy Mass	
L0 Thermal Straps to Cooler	Dummy Mass	
L0 Thermal Strap to Spectrometer Enclosure	As FM	
FPU Mounts	As FM	Supplied by customer
Optical Alignment Cube	As FM	
Harnesses	Dummy Mass	

Dummy masses will be constructed from Aluminium Alloy, and will be mounted internally as per the FM interfaces.

A 3-D CAD model will be generated for the FPU MTD for direct comparison with the FM model. The MTD model will be used to size and place the various dummy masses.

It is proposed that an FEA model for the FPU MTD will not be generated, as it is not likely to differ significantly from the FM FEA model. A matrix will be presented with the delivery documentation showing any variances from the FM model. An FEA analysis will be performed for individual dummy masses if there are likely to be stiffness or stress problems. FEA work performed at RAL will be done using the package ANSYS 6.1 (or higher). If the customer requires the delivery of any models, an export to NASTRAN or a common format will be performed.

#### 4.1.3 Thermal Design

A current ESATAN model of the FM FPU will be altered to reflect the MTD design. Heaters and thermistors will be applied as per AD3. Thermal interfaces between the different stages will use FM designs and materials with the following exceptions:

- The L0 thermal straps to the cooler pump and evaporator will be terminated inside the FPU cover. Resistors will be mounted on the strap-ends to simulate the heat load, as per AD3.
- All thermal straps will be supported as they enter the FPU enclosure with thermally isolating mounts which will ensure the parasitic heat loss is less than 5% of the minimum heat dissipation of the resistor.
- Parasitic heat flow between JFET boxes and BDAs will be simulated with a dummy harness. This harness will be connected at the JFET end using FM type connectors, but will be fixed to the BDA dummies using either an epoxy or mechanical clamp.

This approach will ensure that the thermal behaviour of the MTD is very close to that of the FM

#### 4.1.4 Internal Harness Routing

Routing to internal resistors and thermistors will be subject to thermal design. Parasitic heat loss and ohmic resistance will comply with AD3.

#### 4.2 SPECTROMETER JFET

#### 4.2.1 Overview

The spectrometer JFET will be a dummy mass. The mass will be mounted using FM equivalent isolating feet and fasteners.

#### 4.2.2 Mechanical Design

An Aluminium Alloy plate with FM representative feet will be used for the JFET base. A dummy mass will be attached to this. This mass will be used for mounting the FM representative connectors. The whole assembly will be designed to match the FM in terms of mass, CoG and MoI.

#### 4.2.3 Thermal Design

Thermal interfaces will be the same as the FM, with resistors and thermistors mounted as per AD3. An ESATAN model of the JFET will be produced.

#### **4.3 PHOTOMETER JFET**

#### 4.3.1 Overview

The photometer JFET will be a dummy mass. The mass will be mounted using FM equivalent isolating feet and fasteners.

#### 4.3.2 Mechanical Design

An Aluminium Alloy plate with FM representative feet will be used for the JFET base. A dummy mass will be attached to this. This mass will be used for mounting the FM representative connectors. The whole assembly will be designed to match the FM in terms of mass, CoG and MoI.

#### 4.3.3 Thermal Design

Thermal interfaces will be the same as the FM, with resistors and thermistors mounted as per AD3. An ESATAN model of the JFET will be produced.

## **5. OUTLINE OF WORK**

## 5.1 WORKPACKAGE BREAKDOWN

The following workpackages are proposed:

1000	Management
1100	<ul> <li>Project Management</li> </ul>
1110	<ul> <li>Scheduling and Control</li> </ul>
1120	- Meetings
1200	• PA
1210	<ul> <li>Preparing Procedures</li> </ul>
1220	- Audits
1300	<ul> <li>Documentation</li> </ul>
1310	- ADP
1320	- Reports
1330	- Reviews
2000	Design and analysis
2100	Thermal analysis
2110	- Modelling and design
2120	- Reports
2200	Mechanical analysis
2210	- Collating mass/cog info
2220	- Analysis of subsystems
2230	- Interface load calcs
2240	- Reports
2300	Mechanical Design
2310	- Instrument modelling
2320	- Dummy mass modelling
2330	- Detailing
3000	Manufacture/Procurement
3100	<ul> <li>Structural Parts</li> </ul>
3200	RAL Parts
3210	<ul> <li>Dummy Masses</li> </ul>
3220	- JFET Mounts
3300	<ul> <li>Electrical and Thermal parts/harnessing</li> </ul>
3310	<ul> <li>Electrical Parts Procurement</li> </ul>
3320	<ul> <li>Thermal Parts Procurement</li> </ul>
3400	<ul> <li>Dummy harness assy.</li> </ul>
4000	AIV
4100	<ul> <li>Mechanical Assembly</li> </ul>
4110	- Part cleaning
4120	- Assembly
4130	<ul> <li>Locking/staking</li> </ul>
4140	- Alignment cube

<ul> <li>Assembly of Thermal Parts</li> </ul>
<ul> <li>Electrical Assembly</li> </ul>
<ul> <li>Attach connectors</li> </ul>
<ul> <li>Attach and route internal wires</li> </ul>
<ul> <li>Inspection</li> </ul>
<ul> <li>Electrical checkout</li> </ul>
<ul> <li>Final assembly</li> </ul>
<ul> <li>Mass and C of G</li> </ul>
<ul> <li>Vibration test</li> </ul>
- Test Fixture
- Planning
- Conducting
- Report
Bakeout
<ul> <li>Clean Surfaces</li> </ul>
- Bakeout
- Inspection
- Bagging
GSE
<ul> <li>Transport design and mfr</li> </ul>
- Design
- Procurement
- Assembly
<ul> <li>Handling Equipment</li> </ul>
Delivery
<ul> <li>Delivery and acceptance testing</li> </ul>
Integration
<ul> <li>Post delivery support</li> </ul>

## 5.2 WORKPACKAGE DESCRIPTIONS

The proposed work packages are as follows:

WORK PACKAGE DESCRIPTION		WP No	: 1100
Project:	SPIRE MTD	Date	: 4/Feb/2003
Major Subsystem:	FPU and JFETs		
Subsystem:	-		
WP Title:	Management Scheduling a	nd Control	
WP Start Event:	Authorisation to proceed		
WP End Event:	Project Closed		
WP Manager:	R. Edeson	Organisation Responsible	RAL
WP Aims			
1. Delivery and acce	eptance of Spire MTD as per	contract.	
<u>Inputs</u>			
1. Task estimates from	om WP managers. Quotes fro	om suppliers	
-			
<u>Outputs</u>			
1. Project plan, asso	ciated documents, schedules	, review documents	
2. Regular updates of	on progress to the customer.		
<u>Tasks</u>			
1. 1110 – Schedulin	g and Control, including rou	tine updating of	
schedules for con	nparison with the baseline.		
2. 1120 – Meetings,	including teleconferences.		

WORK PACKAGE DES	SCRIPTION	WP No:	1200			
Project:	SPIRE MTD	Date:	4/Feb/2003			
Major Subsystem:	FPU and JFETs					
Subsystem:						
WP Title:	Product Assurance					
WP Start Event:	Authorisation to proceed					
WP End Event:	Project Closed					
WP Manager:	PA	<b>Organisation Responsible:</b>	RAL			
WP Aims						
1. Conduct the project	et PA activities in order to e	nsure that the design meets the	specified technical			
requirements using	g the SIRE PA PLAN (SPIF	RE-RAL-PRJ-000017) where	applicable			
2 Draw and deliverab	la DA de sum entetions					
2. Prepare deliverad	le PA documentations					
<u>Inputs</u>	с , ,					
1. PA requirements	from customer					
Outrute						
<u>Unipuls</u>	loovmonta with the omnhoe	ia place op relighility opgingeri	na collabrian of			
1. PA plan, felated c materials and test	1. PA plan, related documents, with the emphasis place on reliability engineering selection of materials and test documentation and inspection reports.					
materials and test	materials and test documentation and inspection reports					
Tasks						
1. 1210 – Document	preparation					
This includes a P.	A plan and other procedural	documents.				
2. 1220 – Audits						
This includes any	periodic audits specified in	the PA plan as well as				
general monitorin	g of procedures and report	preparation and				
document control						

WORK PACKAGE DES	SCRIPTION	WP No:	1300		
<b>Project:</b> SPIRE MTD		Date:	4/Feb/2003		
Major Subsystem:	FPU and JFETs				
Subsystem:					
WP Title:	Ongoing Documentation				
WP Start Event:	Kickoff				
WP End Event:	Project closure				
WP Manager:	R. Edeson	<b>Organisation Responsible:</b>	RAL		
WP Aims					
1. To assemble deliv	verable documents				
2.					
<u>Inputs</u>					
1. Ongoing inputs fr	om all WP's				
<u>Outputs</u>					
1. Documents delive	erable throughout the project	t			
2. Documents delive	erable with hardware.				
3. Internal document	3. Internal documents.				
<u>Tasks</u>					
1. 1310 – ADP: Ass	emble documents required in	n the ADP.			
2. 1320 – Reports: C	Generate relevant project rep	orts on schedule.			
3. 1330 – Reviews: reviews.	Prepare for and attend PDR	and CDR level			

WOF	RK PACKAGE DES	CRIPTION	WP No:	2100		
	Project:	SPIRE MTD	Date:	4/Feb/2003		
N	1ajor Subsystem:	FPU and JFETs				
	Subsystem:					
	WP Title:	Thermal Analysis				
	WP Start Event:	Kickoff				
	WP End Event:	Completion of design/ana	alysis			
	WP Manager:	Anne-Sophie Goizel	<b>Organisation Responsible:</b>	RAL		
WP	<u>Aims</u>					
	To assist in the de	sign of the SPIRE Mechan	ical Thermal dummies by:			
1.	Confirming by an dissipation and cr	alysis that the SPIRE Therry yogenic behaviour.	mal mass dummies simulate the	SPIRE instrument		
2.	Providing thermal behaviour.	control subsystem hardwa	re to control and monitor dumm	ies thermal		
3.	Confirming the he testing (electrical)	ater and temperature senso	ors are operational through revie	w of design and		
Inpu	its					
1.	MTD Mechanical	drawings				
2.	Herschel MTD Pr	ocurement Specification ar	nd Statement of Work (Astrium)			
3.	SPIRE Instrument	t Design Requirement and	Specifications document			
4.	Thermal performa analysis report	nces of SPIRE Instrument	for various operating modes – S	PIRE thermal		
0.1						
<u>Out</u>	<u>puts</u>		D			
1.	Simplified Therm	al model of the SPIRE MI				
2.	to the Spire opera	tion timeline).	ude voltage profile for heater ut	lisation according		
3.	Thermal Analysis decoupling L1/L0	Reports describing SPIRE and parasitic loads.	MTD performances in terms of	dissipated heat,		
4.	Acceptance Test I	Report for thermal control h	nardware (electrical).			
5.	Contributions to a	ll mass dummies design th	ermal issues.			
Tagl						
<u>1 ase</u> 1	<u>xə</u> 2110 - Analycic					
1.	Review proposed	mechanical design of MTI	D.			
	Generate simplifie	ed Thermal model of SPIR	E MTD.			
	Provide input for	the L1/L0 decoupling inter	face design.			
	Provide input for	the design of harness betwee	een JFETS and FPU.			
	Support design ev	olution,				
	Analyse MTD the	ermal design and assess pe	ertormances in terms of			
	ussipated heat,	uecoupling LI/LU, para loads at I 0 I 1 and IEET.	asilic loads, interface			
I	temperatures and	iouas at Lo, L1, and J1 L18		I		

<ol> <li>2120 - Reports Report analyses results and attend design review Generate MTD TMM Description report an heater operation voltages during SPIRE operation</li> </ol>	vs. d provide input for on	
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WORK PACKAGE DESCRIPTION	<b>WP No:</b> 2200
<b>Project:</b> SPIRE MTD	<b>Date:</b> 4/Feb/2003
<b>Major Subsystem:</b> FPU and JFETs	
Subsystem:	
<b>WP</b> Title: Mechanical Analysis	
WP Start Event: Kickoff	
WP End Event: Completion of design/analy	rsis
WP Manager: R. Edeson	Organisation Responsible: RAL
WP Aims	
1. Ensure mechanical analysis requirements are n	net
2. Ensure mechanical performance and safety ma	rgin requirements are met.
Inputs	
1. Subsystem interface documents and drawings	
2. 3D CAD model of current FM	
3. FEA report on FM.	
4. Herschel MTD Procurement Specification and	Statement of Work (Astrium)
Outputs	
1 Report on all deviations from the FM FEA mod	del
2 Specific reports on subsystem dummy masses	which require separate analysis.
<u>Tasks</u>	
1. 2210 – Collate all mass and CoG information of	on the FM FPU
model. Define the mass and location for international statements and statements a	al dummy masses.
2. 2220 – Perform FEA analysis on specific intern	nal mass dummies
where necessary to determine compliance with	stiffness w IEETa
2 2220 Calculate interface leads to demonstrat	y JFE IS.
Margin of Safety requirements Use FM FEA r	results
2240 - Reports on mechanical analysis	
22.10 Reports on meenanear analysis.	

WOF	RK PACKAGE DES	CRIPTION	WP No:	2300
	Project:	SPIRE MTD	Date:	4/Feb/2003
N	Iajor Subsystem:	FPU and JFETs		
	Subsystem:			
	WP Title:	Mechanical Design		
	WP Start Event:	Kickoff		
	WP End Event:	Completion		
	WP Manager:	R. Edeson	<b>Organisation Responsible:</b>	RAL
<u>WP</u>	<u>Aims</u>			
1.	To create a CAD	model of the MTD for dir	ect comparison with the flight mo	odel.
2.	To generate dumn	ny mass models and detai	led drawings for SPIRE subsyster	ms.
<u>Inpu</u>	<u>its</u>			
1.	CAD model of FM	A from MSSL		
2.	Interface document	nt of subsystems within S	PIRE.	
3.	SPIRE interface c	ontrol drawings.		
<u>Out</u>	<u>puts</u>			
1.	Full CAD model of	of MTD		
2.	Models of dummy	/ masses		
3.	Detailed drawings	s of dummy parts		
Task	<u>(s</u>			
1.	instrument will be	t modelling – the MSSL C used to produce a Pro-Ei	ngineer model.	
2.	2320 – Dummy m to give FM repres	ass modelling. Dummy n entative mass properties.	nasses will be designed	
3.	2330 – Produce de and manufacture.	etailed drawings of all du	mmy parts for quotation	

WORK PACKAGE DES	CRIPTION	WP No:	3100
Project:	SPIRE MTD	Date:	4/Feb/2003
Major Subsystem:	FPU and JFETs		
Subsystem:			
WP Title:	Structural Parts		
WP Start Event:	Kickoff		
WP End Event:	Acceptance by RAL of s	structural items	
WP Manager:	R. Edeson	<b>Organisation Responsible:</b>	MSSL
WP Aims		8 1	
1. Produce structural	l parts		
Inputs			
1. FM Drawings			
<b>Outputs</b>			
Structural parts			
<u>Tasks</u>			
1. <b>Produce the follo</b>	wing as per FM:		
Photometer cove	r		
Spectrometer cov	ver		
SOB			
Phot. det. box			
Spec. del. box	for PF		
Fasteners clamn			
Ontical supports	5, 00115		
Mounting plate			
FEM (model of t	the FM structure)		

mo			TT IN ST	2200
WOI	RK PACKAGE DES	SCRIPTION	WP No:	3200
	Project:	SPIRE MTD	Date:	4/Feb/2003
N	Aajor Subsystem:	FPU and JFETs		
	Subsystem:			
	WP Title:	RAL Parts		
	WP Start Event:	CDR		
	WP End Event:	Delivery of parts		
	WP Manager:	R. Edeson	<b>Organisation Responsible:</b>	RAL
WP	Aims			
1.	Produce internal a	and JFET dummy masses		
2.	Produce JFET sup	port structures		
Inpu	1 <u>ts</u>			
1.	Detailed drawings	s (WP2430).		
2.	Detailed drawings	s of FM JFET support cor	nponents.	
Out	puts			
1.	Dummy mass part	ts.		
2.	Dummy JFET par	ts		
Tasl	KS			
1.	3210 - Manufactu	re dummy masses in-hou	se or through local	
	contractors. Surfa	ce treatment as necessary		
2.	3220 – Manufactu	are of JFET support struct	tures as per FM drawings	

WORK PACKAGE DES	SCRIPTION	WP N	No: 33	00
Project:	SPIRE MTD	Dat	te: 4/	Feb/2003
Major Subsystem:	FPU and JFETs			
Subsystem:				
WP Title:	Electrical and Thermal Pa	rts Procurement		
WP Start Event:	Kickoff			
WP End Event:	Arrival of parts at RAL			
WP Manager:	J. Firth	Organisation Responsib	le: R	AL
WP Aims				
1. Procure electrical	parts			
<u>Inputs</u>				
1. Procurement Spec	cification (Astrium doc. No.	HP-2-ASED-PS-0027		
<u>Outputs</u>				
1. Parts in electronic	e store.			
<u>Tasks</u>				
1. 3310 - Procure Co	onnectors			
2. 3320 – Procure th	ermistors and heaters			

WOF	RK PACKAGE DES	SCRIPTION	WP	No:	3400
	Project:	SPIRE MTD	D	ate:	4/Feb/2003
N	<b>Iajor Subsystem:</b>	FPU and JFETs			
	Subsystem:				
	WP Title:	Dummy Harness Manufac	cture		
	WP Start Event:	CDR			
	WP End Event:	Completion of harness			
	WP Manager:	John Firth	<b>Organisation Responsi</b>	ble:	RAL
WP	Aims				
1.	Produce dummy h	narnesses from JFETs to FP	U		
Inpu	<u>its</u>				
1.	Thermal Report				
2.	Electrical ICD				
<u>Out</u>	<u>outs</u>				
	Dummy harnesses	5			
					1
Task	<u> </u>				
1.	Produce dummy h	narnesses between JFETs ar	nd the FPU. Harnesses		
	to be thermally and mechanically representative. Connectors should				
	only be necessary	at the JFE1 ends, with wir	es bonded or		
	incentation any fast		cilus.		

WORK PACKA	AGE DES	CRIPTION	WP	No:	4100
]	Project:	SPIRE MTD	Ι	Date:	4/Feb/2003
Major Sub	system:	FPU and JFETs			
Sub	system:				
W	P Title:	Mechanical Assembly			
WP Start	t Event:	Conclusion of WPs 3000			
WP End	l Event:	Assembly complete			
WP M	anager:	R. Edeson	<b>Organisation Respons</b>	ible:	RAL
WP Aims					
1. Mechani	cally asse	emble the FPU and JFETs			
2.					
<u>Inputs</u>					
1. All parts					
<u>Outputs</u>					
Assembl	ed items				
<u>Tasks</u>					
1. 4110 – C	lean all p	parts to RAL internal spec.			
2. 4120 – A	ssemble	all parts except photometer	and spectrometer		
covers (a	iccess req	uired for wiring).			
3. 4130 – L	ock and s	stake assembly			
4. 4140 – A	ttach and	l align the optical alignment	cube.		

WO	RK PACKAGE DES	SCRIPTION	WP No:	4200
"01	Designet: SDIDE MTD			$\frac{1}{200}$
_	Project:	SPIKE MID	Date:	4/Fe0/2005
N	<b>Iajor Subsystem:</b>	FPU and JFETs		
	Subsystem:			
	WP Title:	Assembly of thermal parts	3	
	WP Start Event:	Completion of mechanica	l assembly (WP4100)	
	WP End Event:	All thermal parts integrate	ed	
	WP Manager:	AS Goizel	Organisation Responsible:	RAL
WP	Aims			
1.	Integrate all therm	nal parts		
2.	-	-		
Inpu	1 <u>ts</u>			
1.	Locations of heate	ers and thermistors from W	P2100	
2.	Mechanical FPU a	assembly without covers.		
Out	outs			
1.	All thermal parts i	integrated		
Task	KS			
1.	Attach all heaters correct locations.	and thermistors to the mech	nanical assembly in the	

WORK PACKAGE DES	SCRIPTION	WP	No:	4300
Project:	SPIRE MTD	D	ate:	4/Feb/2003
Major Subsystem:	FPU and JFETs			
Subsystem:				
WP Title:	Electrical Assembly			
WP Start Event:	Completion of Mechan	ical Assembly (WP4100)		
WP End Event:	Completion of Wiring			
WP Manager:	J. Firth	Organisation Responsi	ble:	RAL
<u>WP Aims</u>				
1. Make all internal	electrical connections			
2.				
<u>Inputs</u>				
1. Mechanical assem	nbly, thermal parts integr	ated		
<u>Outputs</u>				
Complete internal	wiring			
Tasks		· · · ·		
1. $4310 - \text{Attach all}$	connectors as per FM sp			
2. $4320 - \text{Attach all}$	internal wires by soldering	ng or crimping as		
necessary.				

WO	RK PACKAGE DES	SCRIPTION	WP No:	4400	
	Project:	SPIRE MTD	Date:	4/Feb/2003	
N	Aajor Subsystem:	FPU and JFETs			
	Subsystem:				
	WP Title:	Inspection			
	WP Start Event:	Completion of wiring			
	WP End Event:	Inspection successful			
	WP Manager:	J. Firth	<b>Organisation Responsible:</b>	RAL	
WP	Aims				
1.	Check the wiring.				
2.	Check the mechan	nical properties			
Inpu	<u>1ts</u>				
1.	Completion of wi	ring			
<u>Out</u>	<u>puts</u>				
1.	Report on complia	ance with Procurement Spe	ecification		
Tas	<u>KS</u>		TT 1 / 1 1 1		
1.	4410 - Perform	a cneck of the wiring	g. Undertake hardware		
	Milli-ohms resista	ance test			
	Wire-to-wire, wir	e-to-shield and shield-to-sh	nield high voltage		
	isolation resistanc	e test (representative bridg	ses from signal to return		
	lines required for each channel).				
	4420 – Perform the final FPU assembly (attach covers)				
	4430 – Measure n	nass and C of G of the FPU	J as well as JFET		
	dummies.				

WORK PACKAGE	DES	CRIPTION	W	P No:	4500	
Proj	ect:	SPIRE MTD	]	Date:	4/Feb/2003	
Major Subsyst	em:	FPU and JFETs				
Subsyst	em:					
WP T	itle:	Vibration Tests				
WP Start Eve	ent:	Completion of inspection				
WP End Ev	ent:	Completion of vibration te	st			
WP Manag	ger:	R. Edeson	<b>Organisation Respon</b>	sible:	RAL	
WP Aims						
1. Qualify FPU	and.	JFETs as per AD3.				
<u>Inputs</u>						
1. Completion of	of As	sembly				
2. Required test	t leve	ls				
3. FPU mounts	from	customer				
<b>Outputs</b>						
1. Vibration tes	t repo	ort				
<u>Tasks</u>						
1. 4510 – Desig	gn and	d procure test fixtures.				
2. 4520 – Prepa	re tes	st specification				
3. 4530 – Perfo	rm te	sts on JFETs and FPU				
4. 4540 – Gener	rate r	eport				

WORK	PACKAGE DES	CRIPTION	WP No	: 4600	
	<b>Project:</b>	SPIRE MTD	Date	: 4/Feb/2003	
Ma	jor Subsystem:	FPU and JFETs			
	Subsystem:				
	WP Title:	Bakeout			
W	VP Start Event:	Successful completion of	vibration test (WP4500)		
,	WP End Event:	Bagging of FPU and JFET	's for delivery		
	WP Manager:	R. Edeson	Organisation Responsible	: RAL	
WP Ai	i <u>ms</u>				
1. I	Bake out the deliv	erable items as per AD3.			
<u>Inputs</u>	<u> </u>				
1. I	Bakeout temperati	ure levels and tolerances.			
<u>Outpu</u>	ts				
1. I	Bagged deliverabl	es conforming to cleanlines	s requirements		
-					
<u>Tasks</u>					
1. 4	620 - Clean exter	rior surfaces of FPU and JF	ETs.		
2. 4	1620 - Conduct th	e bakeout			
3. 4	. 4630 - Perform cleanliness inspection – verify particulate and				
r	nolecular contam	ination is acceptable.			
4. 4	1640 – Double ba	g deliverable items.			

WORK PA	CKAGE DES	SCRIPTION	WP No:	5100		
	<b>Project:</b>	SPIRE MTD	Date:	4/Feb/2003		
Major	Subsystem:	FPU and JFETs				
	Subsystem:					
	WP Title:	Transport design and manu	ufacture			
WP S	Start Event:	Kickoff				
WP	End Event:	Completion of assembly				
W	P Manager:	R. Edeson	<b>Organisation Responsible:</b>	RAL		
WP Aims						
1. Prov	ide a secure a	and clean transportation syst	em for delivery.			
<u>Inputs</u>						
1. Inter	face control o	documents.				
2. Tran	Transport requirements for deliverables, including cleanliness.					
<u>Outputs</u>						
1. Asse	mbled transp	ort gear				
<u>Tasks</u>						
1. 5110	– Design an	d mfr. transport plates for ea	ch of the deliverables			
2. 5120	– Procure tra	ansport containers and anti-v	vibration mounts.			
3. 5130	– Assemble	transport gear				

WORK PACKAGE DES	SCRIPTION	WP No:	5200				
Project:	SPIRE MTD	Date:	4/Feb/2003				
Major Subsystem:	FPU and JFETs						
Subsystem:							
WP Title:	Handling equipment						
WP Start Event:	Kickoff						
WP End Event:	Completion of handling						
WP Manager:	R. Edeson	Organisation Responsible:	RAL				
<u>WP Aims</u>							
1. Provide fixtures for	or the handling of the FPU						
Inputs							
1. Interface control drawings.							
Outputs							
1. Handling fixtures							
Tasks							
1. Design and manua	facture fixtures for the hand	ling of the FPU.					

WORK PACKAGE DES	SCRIPTION	WP No:	6100			
Project:	SPIRE MTD	Date:	4/Feb/2003			
Major Subsystem:	FPU and JFETs					
Subsystem:						
WP Title:	Delivery					
WP Start Event:	Completion of WP4000					
WP End Event:	Acceptance by customer.					
WP Manager:		Organisation Responsible:	RAL			
WP Aims						
1. Deliver FPU and	JFETs					
Inputs						
1. Items bagged and ready for transport						
<u>Outputs</u>						
1. Transport						
<u>Tasks</u>						
1. Transport the deli	verables to Astrium. Help w	ith any acceptance				
testing at the deliv	very point.					

WORK PACKAGE DESCRIPTION		WP No:	6200			
Project:	SPIRE MTD	Date:	4/Feb/2003			
Major Subsystem:	FPU and JFETs					
Subsystem:						
WP Title:	Integration					
WP Start Event:	Customer defined					
WP End Event:	Integration complete					
WP Manager:	R. Edeson	<b>Organisation Responsible:</b>	RAL			
WP Aims		-				
1 Integrate units						
Inputs						
1 Torque settings locking instructions and other integration information						
Outputs						
1 Integrated units						
1. Integrated units						
Tasks						
	te the FM Hereitel OD er					
1. Fix the dummies	to the FM Herschel OB as	per Fivi unit				
specifications.						

WORK PACKAGE DE	SCRIPTION	WP No:	6300				
Project	SPIRE MTD	Date:	4/Feb/2003				
Major Subsystem:	FPU and JFETs						
Subsystem							
WP Title:	Post delivery support						
WP Start Event:	Customer defined						
WP End Event:	Customer defined						
WP Manager:	R. Edeson	<b>Organisation Responsible:</b>	RAL				
WP Aims							
1. Provided and su	port required after integration	ion.					
<u>Inputs</u>							
1. Future customer	requirements						
Outputs							
1. Assistance to cus	stomer.						
Tasks							
1. Provide information	1. Provide information and/or services to the customer at a later point						
in the SPIRE pro	gram.	_					

## 6. PROPOSED MAIV PROGRAMME

#### 6.1 MANUFACTURE AND PROCUREMENT

#### 6.1.1 Procurement of structure

Flight Model parts to be supplied by subcontractors.

#### 6.1.2 Manufacture of dummy parts

Dummy masses will be made in-house, or by local contractors. All parts will be given an Alocrom surface finish.

#### 6.1.3 Procurement of thermal straps

All thermal straps and isolating support structures will be manufactured in-house or by local contractors.

#### 6.1.4 Procurement of resistors, thermistors and connectors

These parts will comply with AD3. Where possible, they will be sourced through the Herschel Common Parts Procurement Programme.

#### 6.2 ASSEMBLY

#### 6.2.1 General

Assembly will take place at RAL. All assembly will take place in Class 100 conditions.

#### 6.2.2 Mechanical

Mechanical assembly will follow FM assembly procedures. The FM fastener locking philosophy will be followed.

#### 6.2.3 Harnessing

Internal harnessing for resistors and thermistors will be done in-situ.

#### 6.2.4 Thermal

Resistors and thermistors will be attached as per the manufacturer's specifications.

#### 6.2.5 Cleaning

The RAL procedure for cleaning hardware parts will be followed. For metallic parts, this will include rinsing in acetone, ultrasonically in detergent, de-ionised water and alcohol. The baking out of parts prior to assembly will also be considered, since higher bakeout temperatures will be possible for externally exposed metallic parts without harnessing, electrical parts and locking or staking compounds.

#### 6.3 VERIFICATION

#### 6.3.1 Mechanical Inspection

Center of Gravity and Mass measurements will be made in the RAL cleanroom.

#### 6.3.2 Electrical

Electrical connections will be tested before final integration of the external covers. Resistor values will be checked through connector pins.

#### 6.3.3 Thermal

Thermal verification will be by analysis. Thermal vacuum or balance tests will not be conducted by RAL.

#### 6.3.4 Vibration Test

The FPU and JFETs will undergo qualification level vibration testing at room temperature in air as per AD3. The tests will be carried out at RAL's vibration test facility.

#### 6.3.5 Cleanliness

The surface contamination allowed of 50 ppm corresponds (from MIL-STD-1246B) to a maximum exposure of 31 days to Class 100 conditions. When not being worked on, parts and assemblies will be bagged or covered.

Other sources of contamination will be during transport and testing. Contamination will be minimised by double bagging items when leaving the assembly area. The vibration test will be conducted with test items double-bagged.

The FPU and JFETs will be thoroughly cleaned externally with isopropyl alcohol and baked out together as per AD3.

#### 6.3.6 Verification of cleanliness

Surface contamination will be assessed using a tape-peeling test. Molecular contamination will be assessed using witness mirrors and infra-red spectroscopy. The locations on the structures for these tests to take place, as well as the frequency of testing are both TBD. RAL has the capacity to perform both these tests.

#### 6.4 DELIVERY AND INTEGRATION

#### 6.4.1 Transport

The FPU and JFETs will separately be sealed in double layers of Class 100 bagging material. They will be mounted on clean transport plates which will then be mounted in clean transport containers via anti-vibration mounts. Delivery will be by road.

#### 6.4.2 Integration

A RAL engineer and technician will be made available to integrate the units on the Herschel optical bench either on delivery or with a reasonable period of notice after the delivery.

## 7. COMPLIANCE MATRIX

#### 7.1 GENERAL REQUIREMENTS

Requirement	Title	Compliance	Justification
R-DCG-010	Interface Loads	Yes	Same as FM
R-DCG-020	Cryogenic Interfaces	Yes	Same as FM
R-DCG-030	Thermal Interfaces and	Yes	Analysis

	Behaviour		
R-DCG-040	Electrical Interfaces	Ves	Use of FM wiring instructions
R-DCG-050	Dismountability	Ves	Design
R-DCG-060	Thermal pressure humidity	Ves	Use of material (mainly metallic)
R-DCG-000	Outgassing	Ves	Use of known materials
R-DCG-070	Standard cleaning	Vec	SDAS DA 001
R-DCG-080	Cleaning precedure	Vag	SrAS-rA-001 Sont with proposal
R-DCG-090	Stiffnagg	Tes Vec	Some og EM
R-DCG-100	Summess	Yes	Same as FM
K-DCG-110	Safety factors	Yes	analysis/hand calculations.
R-DCG-120	MOS	Yes	Same as FM, dummy masses by
D D G G 405			analysis/hand calculations.
R-DCG-125	Reliability	Yes	Design
R-DCG-130	Maintainability,	Yes	Same interfaces as FM
R-DCG-140	Lifetime	Ves	Design – materials will be chosen
R Ded 110	Enetine	105	not to degrade over this time
R-DCG-145	Safety	Ves	Handling will be as per FM
R-DCG-150	General I/F	Ves	Interfaces will be the same as FM
R-DCG-160	Brackets I/F	Ves	Information provided with ADP
R-DCG-100	Mounting I/E	Vac	All mountings will be the same as
K-DCO-170		105	FM
R-DCG-180	Mounting I/F characteristics	Yes	Same as FM
R-DCG-190	Material and thickness	Yes	Same as FM
R-DCG-200	Form, fit and envelope	Yes	FPU same as FM
R-DCG-210	Attachment of thermal H/W	Yes	Same as FM
R-DCG-220	Connector location	Yes	By design
R-DCG-230	Connector quality	Yes	FM type connectors will be used
R-DCG-240	Connector types	Yes	FM type connectors will be used
R-DCG-250	Wire connection	Yes	The type of wires to be used is
			TBD pending thermal analysis
R-DCG-260	Wiring test	Yes	Inspection and test
R-DCG-270	Shield interconnections	Yes	Shields to be grounded at one point
		105	only.
R-DCG-280	Thermal design compliance	Yes	Design and analysis
R-DCG-290	Thermal control equipment	Yes	This equipment is to interface
	integration		through the cryo-harness, provided
			by the customer.
R-DCG-300	Used material	Yes	A declared materials list will be
P DCC 210	Thormal offects	Vac	Material properties considered
K-DCG-310	Thermal effects	res	during design.
R-DCG-320	Internal heaters	Yes	Heaters to be mounted as per
			manufacturers instructions
R-DCG-330	Heat capacity accuracy	Yes	By analysis
R-DCG-340	External geometry	Yes	By design
R-DCG-350	Deviation from geometry	Yes	TBD
R-DCG-360	Heat path	Yes	By design – the suggested heaters
			will be used.
R-DCG-370	Internal wiring restraint	Yes	Wires to be tied down where
			necessary

R-DCG-380	Resistors wiring	Yes	Procurement Specification
			suggestions to be followed.
R-DCG-390	Heater redundancy	Yes	Redundant heaters to be used.
R-DCG-400	Reserved areas	Yes	Locations TBD by customer
R-DCG-410	Handling points	Yes	Handling points to be as FM.
R-DCG-420	Handling loads	Yes	Loads will be as FM
R-DCG-430	Non-degradation	Yes	Materials will not degrade (note
			that this requirement potentially
			conflicts with cleanliness
			requirements)
R-DCG-440	Material selection	Yes	All structural materials will be
			aluminium alloy. Stainless steel
			fasteners will be used. Harness and
			connector materials will be as FM.
R-DCG-450	Dissimilar material	Yes	All aluminium structure
R-DCG-460	Composite material	Yes/No	JFET mounting spacers are
			currently being tested.
R-DCG-470	Outgassing	Yes	All materials will be known to have
			TML<1% and CVCM<0.1%
R-DCG-480	Ferro-magnetic material	Yes	Stainless steel fasteners and wires
			will be necessary. Fasteners will be
			metric as far as possible.
R-DCG-490	Provision of shims	Yes	Shims are not required
R-DCG-500	Venting	Yes	Design.
R-DCG-510	Bonding	Yes	All aluminium structure. Shielding
			to be grounded.
R-DCG-520	Workmanship	Yes	By inspection
R-DCG-530	Item marking	Yes	Deliverables will be labelled
R-DCG-540	Connector labelling	Yes	Connectors will be labelled
R-DCG-550	Math. Models	Yes	A thermal model will be provided.
			The mechanical model will be as
			per FM.
R-DCG-560	Parts/materials protection	Yes	Units will be sealed in bags in
			Class 100 area.
R-DCG-570	Marking/labelling procedure	Yes	During part manufacture
R-DCG-580	Marking/labelling	Yes	Permanent labels will be used
R-DCG-590	Serial number	Yes	Serial numbers will be generated
R-DCG-600	Handling procedures	Yes	Procedures to be supplied.
R-DCG-610	Packaging	Yes	During assembly
R-DCG-620	Protection procedures	Yes	With delivery documentation
R-DCG-630	Data package	Yes	With delivery documentation
R-DCG-640	Handling procedures	Yes	See R-DCG-600
R-DCG-650	Storage conditions	Yes	Design of transport container.
R-DCG-660	Packing	Yes	Design of transport container.
R-DCG-670	Transportation	Yes	Design of transport container

## 7.2 FPU SPECIFIC REQUIREMENTS

Requirement	Title	Compliance	Justification
R-DSF-010	Alignment cube	Yes	As FM

R-DSF-020	Dimensions	Yes	FM structure design is used
R-DSF-030	Mass	Yes	Test
R-DSF-040	CoG	Yes	Test
R-DSF-050	MoI	Yes	CAD model
R-DSF-060	Eigenfrequency	Yes	FM FEA model
R-DSF-070	Cleanliness	Yes	Cleaning procedures; test/inspection
R-DSF-080	Design loads	Yes	Analysis/hand calculations
R-DSF-090	Test loads	Yes	Test
R-DSF-100	Reserved area	Yes	Customer defined
R-DSF-110	Heaters	Yes	Customer recommended resistors
			will be used
R-DSF-120	Heater location	Yes	Thermal design
R-DSF-130	Parasitic heat	Yes	Thermal design
R-DSF-140	Dissipated heat	Yes	Thermal design
R-DSF-150	L0/L1 I/F decoupling	Yes	I/F either identical to FM or
			through thermal design (strap
			supports)
R-DSF-160	Internal temp. sensors	Yes	The specified sensors will be used
R-DSF-170	Heaters	Yes	The specified heaters will be used
R-DSF-180	Connectors	Yes	The specified connectors will be used

## 7.3 SPECTROMETER JFET SPECIFIC REQUIREMENTS

Requirement	Title	Compliance	Justification
R-DSS-010	Dimensions	Yes	Design of dummy mass envelope.
R-DSS-020	Mass	Yes	Test
R-DSS-050	Eigenfrequency	Yes	Analysis
R-DSS-060	Cleanliness	Yes	Cleaning procedures;
			test/inspection
R-DSS-070	Design loads	Yes	Analysis
R-DSS-080	Test loads	Yes	Test
R-DSS-090	Reserved area	Yes	Customer defined
R-DSS-100	Heaters	Yes	Customer recommended resistors
			will be used
R-DSS-110	Dissipated heat	Yes	Thermal design
R-DSS-120	Internal temp. sensors	Yes	The specified sensors will be used
R-DSS-130	Heaters	Yes	The specified heaters will be used
R-DSS-140	Connectors	Yes	The specified connectors will be
			used

## 7.4 PHOTOMETER JFET SPECIFIC REQUIREMENTS

Requirement	Title	Compliance	Justification

Ref:SPIRE-RAL-PRJ-001526Issue:1Date:10 Feb 2003Page:38

R-DSS-010	Dimensions	Yes	Design of dummy mass envelope.
R-DSS-020	Mass	Yes	Test
R-DSS-050	Eigenfrequency	Yes	Analysis
R-DSS-060	Cleanliness	Yes	Cleaning procedures;
			test/inspection
R-DSS-070	Design loads	Yes	Analysis
R-DSS-080	Test loads	Yes	Test
R-DSS-090	Reserved area	Yes	Customer defined
R-DSS-100	Heaters	Yes	Customer recommended resistors
			will be used
R-DSS-110	Dissipated heat	Yes	Thermal design
R-DSS-120	Internal temp. sensors	Yes	The specified sensors will be used
R-DSS-130	Heaters	Yes	The specified heaters will be used
R-DSS-140	Connectors	Yes	The specified connectors will be
			used

# 8. RISKS

The following technical risks to the project have been identified:

Risk	Description	Management Strategy
Subcontractor	Subcontractor part lead times	Procure FM type structure parts soon after
parts	cause late delivery	kickoff.
Electronic/	Electronic/thermal part lead	Procure these parts soon after kickoff.
thermal parts	times cause late delivery	
Cleanliness	Non – compliance;	Class 100 assembly
		IPA wipe – bakeout
		Possible bakeout required for Al alloy parts
		prior to assembly
Cleanliness	Inability to verify compliance	Use Astrium's suggested method for assessing
verification	by test or inspection.	particle contamination.
		world und contamination may be difficult to
		transform IP spectroscopy or dual quartz
		crustal)
		A cleanliness plan might be required
Wiring	Conflict between parasitic	Unlikely as much larger hundles will be routed
winng	heat loss and ohmic resistance	in the FM so heat loss will be greater there
	properties of wire	in the rate, so near loss will be greater there.
Wiring difficult	Connecting stainless wire may	Practice making these joints before MTD wiring
	be problematic – we may need	takes place.
	to practice	in the F line of the second seco
FPU structure	Import of CAD geometry	There is some slack on the mechanical design
Information	from MSSL may cause	tasks. Use this as contingency to sort out CAD
unavailable	problems	problems.
FPU FM	We need to outline difference	There is a long slack period while thermal work
mechanical	between the FM FEA model	is being done. This time would be used to re-
analysis	and the MTD.	generate relevant parts of the FEA model.
unavailable		
Vibration test	If the RAL shaker is not big	Investigate shake at Astrium Stevenage.
need to be done	enough, or unable to design a	
elsewhere	suitable mount	
Vibration failure	Failure during test	STM will be tested before the MTD.
First mode too	If the first mode of vibration is	The same will probably be true of the FM. If the
low	lower than 120 Hz	FIM is different, we will need to design in some
EM design	Design of the EM structure	Change schedule to accommodate re-design
changes	changes after we have	Change schedule to accommodate re-design.
changes	designed or procured parts	
Thermal analysis	The current model is not	Contingency at end of schedule
Thermal analysis	sufficient and a new one is	contingency at end of schedule.
	required from scratch	
L0-L1 thermal	It might be difficult to isolate	This analysis work should be done early on in
isolation	thermal straps	the task, so any iteration with mechanical design
	1	does not impact the schedule.
Cube Alignment	Alignment of cube may pose	This level of alignment should be easy to
	problems.	achieve. Use FM design.

## 9. PROPOSED PRODUCT ASSURANCE PLAN

The proposed PA plan is the SPIRE instrument plan, doc no SPIRE-RAL-PRJ-000017.

# **10. DELIVERABLE ITEMS**

Item	Description	Quantity	Comments
1	FPU MTD	1	
2	Spectrometer JFET MTD	1	Includes mounting feet
3	Photometer JFET MTD	1	Includes mounting feet
4	Harness	2	
6	Documentation	Refer to Statement of Work.	As required in AD2
7	Transport Containers	3	Containers suitable for the transport and storage of all three MTDs
8	MGSE	As Required	Handling plates for FPU as per FM